

N-Channel Super Trench Power MOSFET

Description

The HMS40N10D uses **Super Trench** technology that is uniquely optimized to provide the most efficient high frequency switching performance. Both conduction and switching power losses are minimized due to an extremely low combination of $R_{\text{DS(ON)}}$ and Q_g . This device is ideal for high-frequency switching and synchronous rectification.

General Features

V_{DS} =100V,I_D =40A

 $R_{DS(ON)}$ =7.2m Ω (typical) @ V_{GS} =10V $R_{DS(ON)}$ =9.5m Ω (typical) @ V_{GS} =4.5V

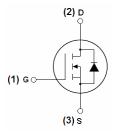
- Excellent gate charge x R_{DS(on)} product(FOM)
- Very low on-resistance R_{DS(on)}
- 175 °C operating temperature
- Pb-free lead plating
- 100% UIS tested

Application

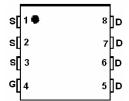
- DC/DC Converter
- Ideal for high-frequency switching and synchronous rectification

100% UIS TESTED!

100% ΔVds TESTED!



Schematic diagram



Marking and pin assignment



DFN5X6-8L top view

Package Marking and Ordering Information

	<u> </u>				
Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HMS40N10D	HMS40N10D	DFN5X6-8L	-	-	=

Absolute Maximum Ratings (T_C=25 ℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	100	V
Gate-Source Voltage	V _G s	±20	V
Drain Current-Continuous	I _D	40	Α
Drain Current-Continuous(T _C =100 °C)	I _D (100℃)	28	Α
Pulsed Drain Current	I _{DM}	120	Α
Maximum Power Dissipation	P _D	125	W
Derating factor		0.83	W/℃
Single pulse avalanche energy (Note 5)	E _{AS}	320	mJ
Operating Junction and Storage Temperature Range	T_{J}, T_{STG}	-55 To 175	$^{\circ}$ C





Thermal Characteristic

Thermal Resistance, Junction-to-Case (Note 2)	R _{eJC}	1.2	°C/W	
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Electrical Characteristics (T_C=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA	100		-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =100V,V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$	1.2	1.7	2.2	V
Duite October Duite Duite	Б	V _{GS} =10V, I _D =39A	-	7.2	8.5	mΩ
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =4.5V, I _D =39A	-	9.5	12	mΩ
Forward Transconductance	g FS	V _{DS} =10V,I _D =39A	40	-	-	S
Dynamic Characteristics (Note4)						
Input Capacitance	C _{lss}	\/ -50\/\/ -0\/	-	4200	5480	PF
Output Capacitance	Coss	V_{DS} =50V, V_{GS} =0V, F=1.0MHz	-	354	425	PF
Reverse Transfer Capacitance	C _{rss}	F=1.UMHZ	-	23	30	PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	t _{d(on)}		-	15	-	nS
Turn-on Rise Time	t _r	V_{DD} =50 V , I_D =39 A	-	10	-	nS
Turn-Off Delay Time	t _{d(off)}	V_{GS} =10V, R_{G} =4.7 Ω	-	41	-	nS
Turn-Off Fall Time	t _f		-	6	-	nS
Total Gate Charge	Qg	\/ -F0\/ -20A	-	65		nC
Gate-Source Charge	Q_{gs}	$V_{DS}=50V, I_{D}=39A,$	-	15.3		nC
Gate-Drain Charge	Q_{gd}	V _{GS} =10V	-	9		nC
Drain-Source Diode Characteristics	<u> </u>		•			
Diode Forward Voltage (Note 3)	V_{SD}	V _{GS} =0V,I _S =40A	-		1.2	V
Diode Forward Current (Note 2)	Is		-	-	40	Α
Reverse Recovery Time	t _{rr}	T _J = 25°C, I _F = I _S	-	101		nS
Reverse Recovery Charge	Qrr	$di/dt = 100A/\mu s^{(Note3)}$	-	193		nC

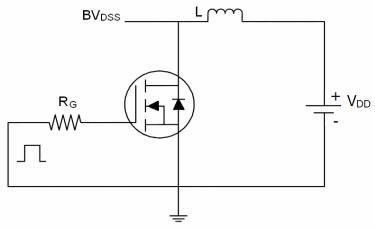
Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- 3. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2%.
- 4. Guaranteed by design, not subject to production
- 5. EAS condition : Tj=25 $^{\circ}\text{C}$,V_DD=50V,V_G=10V,L=0.5mH,Rg=25 Ω

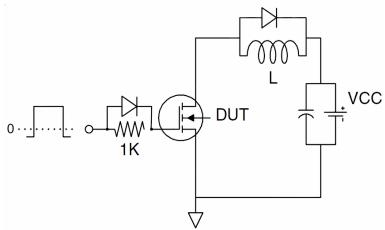


Test Circuit

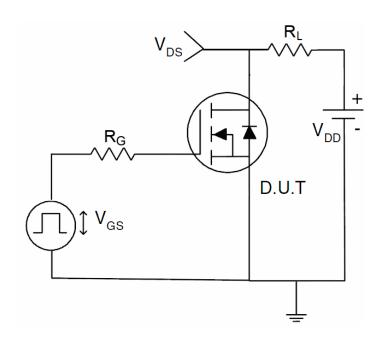
1) E_{AS} test Circuit



2) Gate charge test Circuit



3) Switch Time Test Circuit





Typical Electrical and Thermal Characteristics

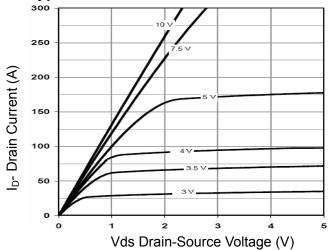


Figure 1 Output Characteristics

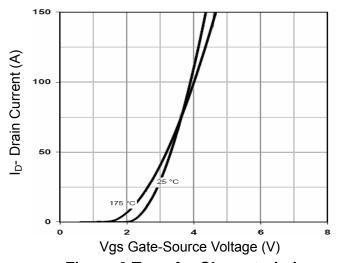


Figure 2 Transfer Characteristics

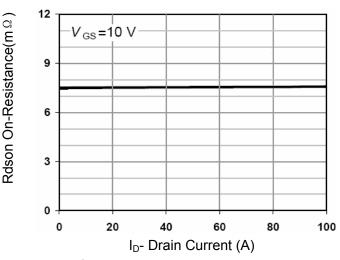


Figure 3 Rdson- Drain Current

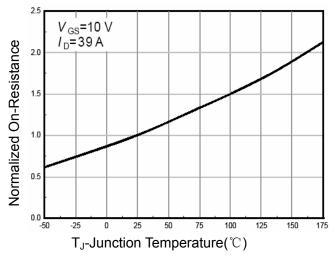


Figure 4 Rdson-JunctionTemperature

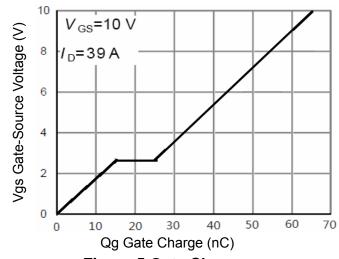


Figure 5 Gate Charge

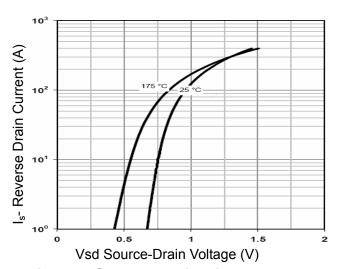


Figure 6 Source- Drain Diode Forward



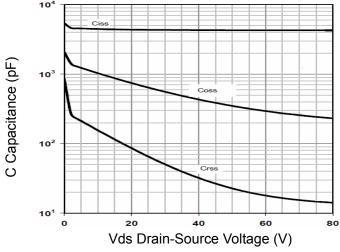


Figure 7 Capacitance vs Vds

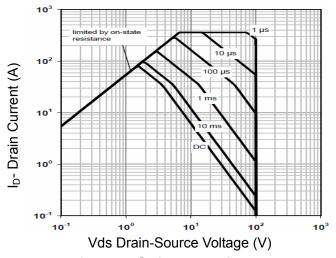


Figure 8 Safe Operation Area

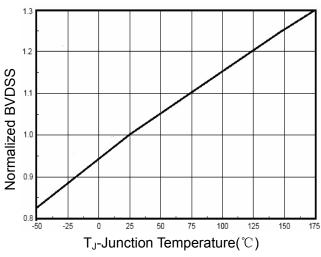


Figure 9 BV_{DSS} vs Junction Temperature

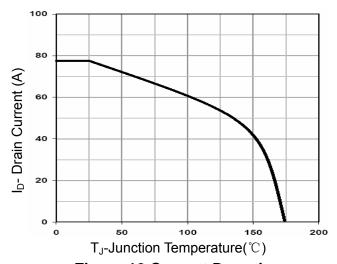


Figure 10 Current De-rating

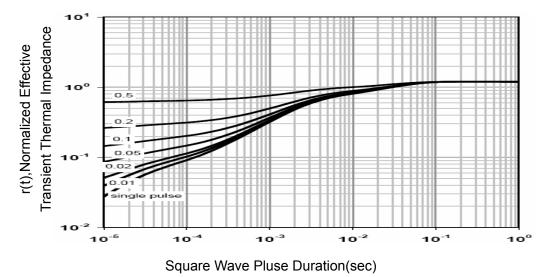
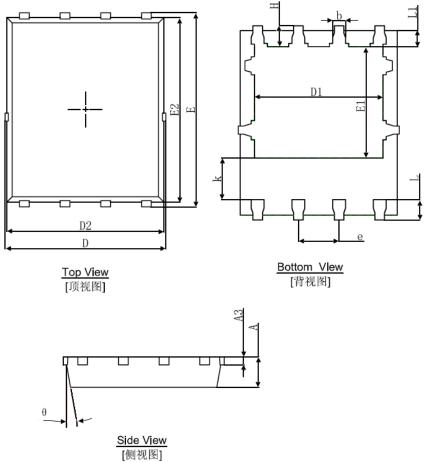


Figure 11 Normalized Maximum Transient Thermal Impedance



DFN5X6-8L Package Information



	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
Α	0.900	1.000	0.035	0.039	
A3	0.254	4REF. 0.010REF.		REF.	
D	4.944	5.096	0.195	0.201	
Е	5.974	6.126	0.235	0.241	
D1	3.910	4.110	0.154	0.162	
E1	3.375	3.575	0.133	0.141	
D2	4.824	4.976	0.190	0.196	
E2	5.674	5.826	0.223	0.229	
K	1.190	1.390	0.047	0.055	
b	0.035	0.450	0.014	0.018	
е	1.270(TYP.)				
L	0.559	0.711	0.022	0.028	
L1	0.424	0.576	0.017	0.023	
H	0.574	0.726	0.023	0.029	
θ	8°	12°	8°	12°	

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